Docket No.

245455US2

IN RE APPLICATION OF: Hitoshi ISHIBASHI, et al.

SERIAL NO: 10/722,490

FILED:

November 28, 2003

FOR:

ALIGNMENT PATTERN DETECTING SENSOR, METHOD OF DETERMINING ACCEPTANCE WIDTH OF

THE ALIGNMENT PATTERN DETECTING SENSOR, METHOD OF FORMING ALIGNMENT PATTERN,

AND IMAGE FORMING APPARATUS

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

Transmitted herewith is an amendment in the above-identified application.

No additional fee is required

☐ Small entity status of this application under 37 C.F.R. §1.9 and §1.27 is claimed.

☐ Additional documents filed herewith:

The Fee has been calculated as shown below:

CLAIMS	CLAIMS REMAINING		HIGHEST NUMBER PREVIOUSLY PAID	NO. EXTRA CLAIMS		RATE		CALCULATIONS
TOTAL	36	MINUS	38	0	х	\$50	=	\$0.00
INDEPENDENT	5	MINUS	5	0	х	\$200	=	\$0.00
		☐ MULTIPL	E DEPENDENT	CLAIMS	+	\$360	=	\$0.00
			TOTAL	OF ABOVE CA	LC	JLATIC	NS	\$0.00
		☐ Reduction	by 50% for filing	ing by Small Entity				\$0.00
		☐ Recordation	on of Assignment		+	\$40	=	\$0.00
			//±8 = .			ТОТ	AL	\$0.00

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- ☐ Credit card payment form is attached to cover the fees in the amount of **\$0.00**
- Please charge any additional Fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.
- If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time may be charged to Deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.

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DOCKET NO: 245455US2

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

HITOSHI ISHIBASHI, ET AL. : EXAMINER: GARCIA, R. JR.

SERIAL NO: 10/722,490

FILED: NOVEMBER 28, 2003 : GROUP ART UNIT: 2853

FOR: ALIGNMENT PATTERN
DETECTING SENSOR, METHOD OF
DETERMINING ACCEPTANCE WIDTH
OF THE ALIGNMENT PATTERN
DETECTING SENSOR, METHOD OF
FORMING ALIGNMENT PATTERN, AND
IMAGE FORMING APPARATUS

AMENDMENT

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated October 3, 2005, please amend the aboveidentified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 10 of this paper.